

Test Advantage is recognized as a key provider in enabling Adaptive Test Strategies within the semiconductor test environment

The 2007 International Test Conference brought significant emphasis to the growing demand for employing “Adaptive Test” strategies to optimize semiconductor test, both in terms of cost and quality. A common thread exposed during multiple sessions at the ITC conference, and among key members attending a Die Products Consortium session held during that same week, was the compelling benefits for leveraging Advanced Variance Detection data for improving the semiconductor test processes. Historically, outlier detection methods may have only been considered economically viable in operations that demanded extreme quality standards dictated by “Zero Defect” initiatives associated with specific markets such as Automotive and Medical. These conference sessions rationalized broad market appeal for employing Adaptive Test strategies leveraging Advanced Variance Detection classification methods for both commercial and high reliability markets.

Test Advantage was honored to participate as an invitee to the DPC session and was pleased to witness continued significant reinforcement from the DPC organization for Advanced Variance Detection techniques which could be leveraged in feed forward test strategies. Test Advantage is a world proven leader in providing a user definable Advanced Variance Detection platform that integrates easily within existing semiconductor manufacturing operations.

The text of the press release from the Die Products Consortium session is included below. To learn more about Advanced Variance Detection methodologies, or to facilitate effective deployment of Adaptive Test strategies within your test operation, drop us an email info@testadvantage.com or visit our website at www.testadvantage.com .

Industry Leaders Seeking Adaptive Test Solutions

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Larry Gilg

A subgroup of members of the Die Products Consortium, the AC Defects test team, is focused on a new generation of test and reliability methods for leading edge semiconductor devices known as Adaptive Test. The group sponsored a unique meeting with third party vendors of Adaptive Test solutions in Santa Clara, CA during the 2007 International Test Conference held in October.

Adaptive Test is a term used to describe a broad array of statistical methods for improving semiconductor test by adjusting the test plan based upon feedback from the test environment itself. This is a major departure from traditional test methods that follow a static plan and has come to take on different meanings for different people. The AC Defects group surveyed the various ways in which adaptive test concepts have been

proposed, implemented or anticipated by the member companies' IC testing strategies. The team agreed that, to facilitate an effective evolution of the algorithms, tools and infrastructure that will be required for tomorrow's test challenges the group should provide a summary of the findings to the commercial providers of adaptive test solutions. Three vendors of adaptive test solutions were invited and attended the session: Pintail Technologies, Plano, Texas, OptimalTest, Nes-Ziona, Israel and Test Advantage Inc., Tempe, Arizona held in Santa Clara on October 22, 2007.

During the meeting, representatives of DPC member companies presented the "highest priority" applications of adaptive test from within the DPC subgroup and the corresponding support that is needed from the vendors. The group acknowledged the breadth of methodologies that are currently in use and/or being planned for use. The meeting was considered an important first step in moving the adaptive test solutions into a plug and play mode for IC manufacturers and third party test houses. Discussions are underway regarding potential follow-up meetings and/or activities. For more information, please contact Larry Gilg, Managing Director, DPC.

The Die Products Consortium (DPC) is a program of Dynalog Systems Incorporated. Under the DPC program, Dynalog Systems has invited a group of leading microelectronics companies to collaborate in enlarging the markets for die products worldwide. The DPC is headquartered in Austin, Texas. See www.dieproducts.org.

About Test Advantage

Founded in 1997, Test Advantage develops and deploys leading-edge, proprietary software, including its Streetwise™ and Express™ products, that enable adaptive test strategies for the improvement of manufacturing quality and throughput, throughout the test process. Test Advantage Inc. is the premier provider of software products focused on improving yield, DPPM, and overall test process efficiency, with proven solutions running in production since 2002 and supporting a user base 1000+ testers strong. The Tempe, Arizona-based company operates worldwide, maintaining offices in Germany, France and Singapore. More information about Test Advantage Inc. is available at <http://www.testadvantage.com>, or by calling +1 480-337-3377.